### **NAME**

CUTEST\_cshp - CUTEst tool to evaluate the sparsity pattern of the Hessian of the Lagrangian function.

#### **SYNOPSIS**

CALL CUTEST\_cshp( status, n, m, nnzh, lh, H\_row, H\_col )

## **DESCRIPTION**

The CUTEST\_cshp subroutine evaluates the sparsity pattern of the Hessian of the Lagrangian function  $l(x, y) = f(x) + y^T c(x)$  for the problem, decoded from a SIF file by the script *sifdecoder*, in coordinate format

The problem under consideration is to minimize or maximize an objective function f(x) over all  $x \in \mathbb{R}^n$  subject to general equations  $c_i(x) = 0$ ,  $(i \in 1, ..., m_E)$ , general inequalities  $c_i^l(x) \le c_i(x) \le c_i^u(x)$ ,  $(i \in m_E + 1, ..., m)$ , and simple bounds  $x^l \le x \le x^u$ . The objective function is group-partially separable and all constraint functions are partially separable.

#### **ARGUMENTS**

The arguments of CUTEST\_cshp are as follows

status [out] - integer

the outputr status: 0 for a successful call, 1 for an array allocation/deallocation error, 2 for an array bound error, 3 for an evaluation error,

n [in] - integer

the number of variables for the problem,

m [in] - integer

the total number of general constraints,

nnzh [out] - integer

the number of nonzeros in the Hessian matrix,

lh [in] - integer

the actual declared dimensions of H\_row and H\_col,

**H\_row** [out] - integer

an array which gives the row indices of the nonzeros of the Hessian matrix of the Lagrangian function; only the upper triangular part of the Hessian is stored, and

H col [out] - integer

an array which gives the column indices of the nonzeros of the Hessian matrix of the Lagrangian function corresponding to the row indices in H row.

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## **SEE ALSO**

CUTEst: a Constrained and Unconstrained Testing Environment with safe threads,

N.I.M. Gould, D. Orban and Ph.L. Toint,

Technical Report, Rutherford Appleton Laboratory, 2013.

CUTEr (and SifDec): A Constrained and Unconstrained Testing Environment, revisited,

N.I.M. Gould, D. Orban and Ph.L. Toint,

ACM TOMS, 29:4, pp.373-394, 2003.

CUTE: Constrained and Unconstrained Testing Environment, I. Bongartz, A.R. Conn, N.I.M. Gould and Ph.L. Toint, ACM TOMS, 21:1, pp.123-160, 1995.

cutest\_ush(3M), sifdecoder(1).